

10680339\_CLS

Most Frequently Occurring Classifications of Patents Returned  
From A Search of 10680339 on April 15, 2004

Original Classifications

9	73/105
4	250/306
3	250/234
2	73/1.89
2	250/492.3

Cross-Reference Classifications

8	250/306
7	250/307
5	73/105
3	73/81
3	257/E29.322
2	250/216
2	250/234
2	250/492.2
2	369/126
2	438/48

Combined Classifications

14	73/105
12	250/306
7	250/307
5	250/234
3	73/81
3	250/216
3	250/492.2
3	250/492.3
3	257/E29.322
3	369/126
2	73/1.89
2	216/11
2	250/310
2	324/719
2	438/48

10680339\_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

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14 73/105 (9 OR, 5 XR)  
Class 073 : MEASURING AND TESTING  
73/104 SURFACE AND CUTTING EDGE TESTING  
73/105 .Roughness

12 250/306 (4 OR, 8 XR)  
Class 250 : RADIANT ENERGY  
250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED  
PARTICLES

7 250/307 (0 OR, 7 XR)  
Class 250 : RADIANT ENERGY  
250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED  
PARTICLES  
250/307 .Methods

5 250/234 (3 OR, 2 XR)  
Class 250 : RADIANT ENERGY  
250/200 PHOTOCELLS; CIRCUITS AND APPARATUS  
250/216 .Optical or pre-photocell system  
250/234 ..Means for moving optical system

3 73/81 (0 OR, 3 XR)  
Class 073 : MEASURING AND TESTING  
73/78 HARDNESS  
73/81 .By penetrator or indentor

3 250/216 (1 OR, 2 XR)  
Class 250 : RADIANT ENERGY  
250/200 PHOTOCELLS; CIRCUITS AND APPARATUS  
250/216 .Optical or pre-photocell system

3 250/492.2 (1 OR, 2 XR)  
Class 250 : RADIANT ENERGY  
250/492.1 IRRADIATION OF OBJECTS OR MATERIAL  
250/492.2 .Irradiation of semiconductor devices

3 250/492.3 (2 OR, 1 XR)  
Class 250 : RADIANT ENERGY  
250/492.1 IRRADIATION OF OBJECTS OR MATERIAL  
250/492.3 .Ion or electron beam irradiation

3 257/E29.322 (0 OR, 3 XR)

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Class 257 : ACTIVE SOLID-STATE DEVICES

257/E29.162 ....Insulating materials for IGFET (EPO)

257/E29.166 .Types of semiconductor device (EPO)

257/E29.169 ..Controllable by only signal applied to control electrode (e.g., base of bipolar transistor, gate of field-effect transistor) (EPO)

257/E29.226 ...Unipolar device (EPO)

257/E29.322 ....Single electron transistors: Coulomb blockade device (EPO)

3 369/126 (1 OR, 2 XR)

Class 369 : DYNAMIC INFORMATION STORAGE OR RETRIEVAL

369/99 SPECIFIC DETAIL OF INFORMATION HANDLING PORTION

N

369/126 OF SYSTEM

.Electrical modification or sensing of storage medium (e.g., capacitive, resistive, electrostatic charge)

2 73/1.89 (2 OR, 0 XR)

Class 073 : MEASURING AND TESTING

73/1.01 INSTRUMENT PROVING OR CALIBRATING

73/1.89 .Roughness or hardness

2 216/11 (1 OR, 1 XR)

Class 216 : ETCHING A SUBSTRATE: PROCESSES

216/11 FORMING OR TREATING AN ARTICLE WHOSE FINAL CONFIGURATION HAS A PROJECTION

2 250/310 (1 OR, 1 XR)

Class 250 : RADIANT ENERGY

250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED PARTICLES

250/310 .Electron probe type

2 324/719 (1 OR, 1 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES

RESPONSE REPRESENTATIVE OF ELECTRICAL STIMULUS/RELATIONSHIPS

324/649 .Lumped type parameters

324/691 ..Using resistance or conductance measurement

324/719 ...With semiconductor or IC materials quality determination using conductivity effects

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2 438/48 (0 OR, 2 XR)  
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS

438/48 MAKING DEVICE OR CIRCUIT RESPONSIVE TO  
NONELECTRICAL SIGNAL